of	1
	of

Substitute Form PTO-1449

U.S. Department of Commerce Patent and Trademark Office

Attorney's Docket No. 13909-118001

Application No. 10/625,897

Information Disclosure Statement by Applicant

(Use several sheets if necessary)

Applicant von Bergen et al.

July 24, 2003

Filing Date

Group Art Unit 2186 2167

U.S. Patent Documents Examiner Desig. Document **Publication** Filing Date Class Initial ID Number Date Patentee Subclass If Appropriate AA US-4849905 07-1989 Loeb et al. MR 10-1994 AB US-5355473 Au AC US-5557786 09-1996 Johnson, Jr. MB AD US-5737732 04-1998 Gibson et al.

	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Trans Yes	lation No
mo	AE	0 657 830 A1	06-1995	EPO				

	Other D	ocuments (include Author, Title, Date, and Place of Publication)
Examiner Initial	Desig. ID	Document
mg	AF	Date, C.J., "Introduction to Database Systems, Vol. 1," 1990, Addison Wesley, Reading, MA, USA, paragraph '03.6!, figs. 3.17 and 3.18
ms	AG	Haerder, Theo and Erhard Rahm, "Datenbanksysteme," 1999, Springer, Heidelberg, pp. 207-210, 227-233, figs. 7.15, 8.1 and 8.2.B, English translation provided, 10 pgs.
	AH	
	AI	

Examiner Signature	
MUNITE	~ .∩e. /
Y V WWW	march -

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet	1	of	1
OTTOCE		O1	

Supstitute Form PTO 4449 (Modified)

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 13909-118001

Application No. 10/625,897

Information Disclosure Statement
by Applicant
(Use several sheets if necessary)

Applicant von Bergen et al.

Group Art Unit

(37 CFR §1.98(b))

Filing Date
July 24, 2003

2186 2187

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
MB	AA	US-2002/0032676 A1	03/14/2002	Wheat et al.			

	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner	Desig.	Document	Publicatio	Country or			Trans	lation
Initial	ID d	Number	n Date	Patent Office	Class	Subclass	Yes	No
MB	AB	WO 02/061612 A	08/08/2002	WIPO				
MB	AC	WO 02/061613 A	08/08/2002	WIPO			<u>.</u>	

	Other D	ocuments (include Author, Title, Date, and Place of Publication)
Examiner	Desig.	
Initial	ID D	Document

Examiner Signature	Date Considered
Matthe Bradley	10/1405
EXAMINER: Initials citation considered. Draw line through citation if no	

next communication to applicant.